

PCTEST ENGINEERING LABORATORY, INC.

6660-B Dobbin Road, Columbia, MD 21045 USA Tel. 410.290.6652 / Fax 410.290.6554 http://www.pctestlab.com



HEARING AID COMPATIBILITY

Applicant Name:

LG Electronics MobileComm U.S.A 1000 Sylvan Avenue Englewood Cliffs, NJ 07632 United States Date of Testing: 7/25/2013 Test Site/Location: PCTEST Lab, Columbia, MD, USA Test Report Serial No.: 0Y1307251417-R1.ZNF

FCC ID:

ZNFC410

APPLICANT:

LG ELECTRONICS MOBILECOMM U.S.A

Scope of Test: Application Type: FCC Rule Part(s): HAC Standard: EUT Type: Model(s): Test Device Serial No.:

Audio Band Magnetic Testing (T-Coil) Certification CFR § 20.19(b) ANSI C63.19-2011 Portable Handset LG-C410, LGC410, C410 *Pre-Production Sample* [S/N: 302KPGS332103]

C63.19-2011 HAC Category:

T4 (SIGNAL TO NOISE CATEGORY)

Note: This revised Test Report (S/N: 0Y1307251417-R1.ZNF) supersedes and replaces the previously issued test report on the same subject EUT for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Test results reported herein relate only to the item(s) tested. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. North American Bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez President



FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 1 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 1 01 30
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1.	INTRODUCTION	3
2.	TEST SITE LOCATION	4
3.	EUT DESCRIPTION	5
4.	ANSI C63.19-2011 PERFORMANCE CATEGORIES	6
5.	METHOD OF MEASUREMENT	8
6.	FCC 3G MEASUREMENTS	18
7.	TEST SUMMARY	19
8.	MEASUREMENT UNCERTAINTY	24
9.	EQUIPMENT LIST	25
10.	CALIBRATION CERTIFICATES	26
11.	CONCLUSION	33
12.	REFERENCES	34
13.	TEST SETUP PHOTOGRAPHS	36

FCC ID: ZNFC410	<u> PCTEST</u>	HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 2 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 2 01 50
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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- **RF** Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid in-vitu

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 3 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 5 01 56	
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2. TEST SITE LOCATION

I. Introduction

The map at the right shows the location of the PCTEST LABORATORY in Columbia, Maryland. It is in proximity to the FCC Laboratory, the Baltimore-Washington International (BWI) airport, the city of Baltimore and Washington, DC (See Figure 2-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility in Stonewood Business Center, Guilford Industrial Park, Columbia, Maryland. The site address is 7185 Oakland Mills Road, Columbia, MD 21046. The test site is one of the highest points in the Columbia area with an elevation of 390 feet above mean sea level. The site coordinates are 39° 10' 24" N latitude and 76° 49' 50" W longitude. The facility is 0.4 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory.

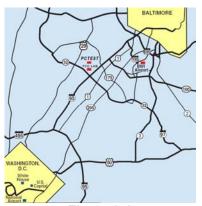


Figure 2-1 Map of the Greater Baltimore and Metropolitan Washington, D.C. area

II. Test Facility / Accreditations:

Measurements were performed at an independent accredited PCTEST Engineering Lab located in Columbia, MD, U.S.A.



(A) made

- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing-Aid Compatibility (HAC), Long-Term Evolution (LTE), CTIA Test Plans, and wireless testing for FCC and Industry Canada Rules.
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST facility is an FCC registered (PCTEST Reg. No. 90864) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (IC-2451).
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
 PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to PCTEST TCB is a Telecommunication Body (TCB) accredited to PCTEST TCB is a Telecommunication Body (TCB) accredited to PC
 - PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and all Industry Canada Standards (RSS).
 - PCTEST facility is an IC registered (IC-2451) test laboratory with the site description on file at Industry Canada.

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 4 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		r aye 4 01 30
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EUT DESCRIPTION 3.



FCC ID:	ZNFC410
Applicant:	LG Electronics MobileComm U.S.A
	1000 Sylvan Avenue
	Englewood Cliffs, NJ 07632
	United States
Model(s):	LG-C410, LGC410, C410
Serial Number:	302KPGS332103
HW Version:	1.1
SW Version:	LGC410-V07e-JUL-12-2
Antenna:	Internal Antenna
HAC Test Configurations:	GSM 850, 128, 190, 251, BT Off
	GSM 1900, 512, 661, 810, BT Off
	UMTS V, 4132, 4183, 4233, BT Off
	UMTS II, 9262, 9400, 9538, BT Off
EUT Type:	Portable Handset

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Voice over Digital Transport OTT Capability	WIFI Low Power	Additional GSM Power Reduction
	850	VO	Yes	Yes: BT	N/A		
GSM	1900		10	105			N/A
	EDGE	DT	N/A	Yes: BT	Yes		
	850	vo	Yes	Yes: BT	N/A		
UMTS	1900	vo	res	Tes. BI	N/A	N/A	N/A
	HSDPA	DT	N/A	Yes: BT	Yes		
BT	2450	DT	No	Yes: GSM or UMTS	N/A	N/A	N/A
Type Transport							

VO = Voice Only DT = Digital Data - Not intended for CMRS Service

Table 3-1: ZNFC410 Air Interfaces

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	💽 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 5 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 5 01 50
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4. ANSI C63.19-2011 PERFORMANCE CATEGORIES

I. MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be \geq -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz - 3000 Hz per §8.3.2.

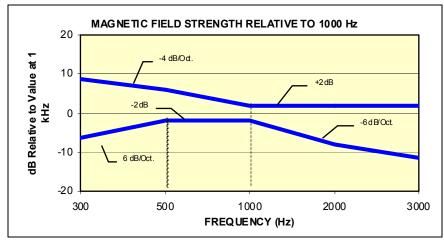


Figure 4-1 Magnetic field frequency response for Wireless Devices with an axial field ≤ -15 dB (A/m) at 1 kHz

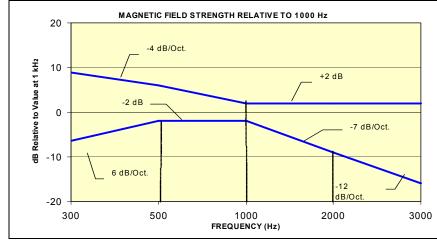


Figure 4-2

Magnetic Field frequency response for wireless devices with an axial field that exceeds -15 dB(A/m) at 1 kHz

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 6 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 0 01 30
© 2013 PCTEST Engineerin	a Laboratory Inc			REV 7 011

Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters			
	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]			
T1	0 to 10 dB			
T2	10 to 20 dB			
Т3	20 to 30 dB			
T4	> 30 dB			
Table 4-1 Magnetic Coupling Parameters				

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 7 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage / 01 30
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METHOD OF MEASUREMENT 5.

I. **Test Setup**

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

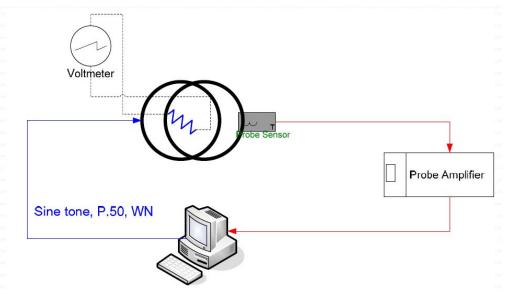
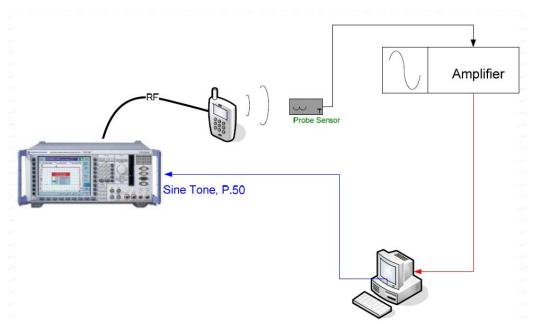


Figure 5-1 Validation Setup with Helmholtz Coil





FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Dago 9 of 29	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Page 8 of 38	
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Scanning Mechanism

Manufacturer:	ТЕМ
Accuracy:	± 0.83 cm/meter
Minimum Step Size:	0.1 mm
Maximum speed	6.1 cm/sec
Line Voltage:	115 VAC
Line Frequency:	60 Hz
Material Composite:	Delrin (Acetal)
Data Control:	Parallel Port
Dynamic Range (X-Y-Z):	45 x 31.75 x 47 cm
Dimensions:	36" x 25" x 38"
Operating Area:	36" x 49" x 55"
Reflections:	< -20 dB (in anechoic chamber)

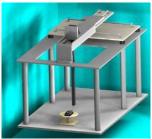


Figure 5-3 RF Near-Field Scanner

ITU-T P.50 Artificial Voice II.

Manufacturer:	ITU-T
Active Frequency Range:	100 Hz – 8 kHz
Stimulus Type:	Male and Female, no spaces
Single Sample Duration:	20.96 seconds
Activity Level:	100%

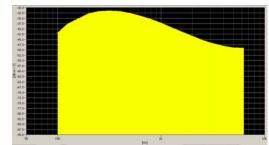


Figure 5-4 Spectral Characteristic of full P.50

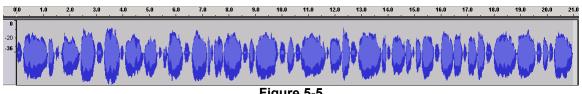


Figure 5-5 **Temporal Characteristic of full P.50**

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Dago 0 of 29	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Page 9 of 38	
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ABM1 Measurement Block Diagram:

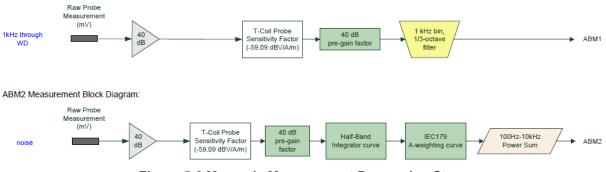


Figure 5-6 Magnetic Measurement Processing Steps

III. **Test Procedure**

- 1. Ambient Noise Check per C63.19 §7.3.1
 - a. Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
 - "A-weighting" and Half-Band Integration was applied to the measurements. b.
 - Since this measurement was measured in the same method as ABM2 measurements, C. this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is: -18 - 30 - 10 = -58 dBA/m

- 2. Measurement System Validation (See Figure 5-1)
 - a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
 - b. ABM1 Validation

The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_{c} = \frac{NI}{r\sqrt{1.25^{3}}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^{3}}}$$

Where H_c = magnetic field strength in amperes per meter N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.13m; R=10.193Ω and using V=29mV:

$$H_c = \frac{20 \cdot (\frac{0.029}{10.193})}{0.13 \cdot \sqrt{1.25^3}} = 0.31623A / m \approx -10dB(A / m)$$

Therefore a pure tone of 1kHz was applied into the coils such that 29 mV was observed across the 10 Ω resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe measurement at -10 dB(A/m). This was verified to be within \pm 0.5 dB of the -10 dB(A/m) value (see Page 23).

FCC ID: ZNFC410	<u> PCTEST</u>	HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 10 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 10 01 50
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c. Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1 kHz, between 300 - 3000 Hz using the ITU-P.50 artificial speech signal as shown below:



Figure 5-7 Frequency Response Validation

d. ABM2 Measurement Validation

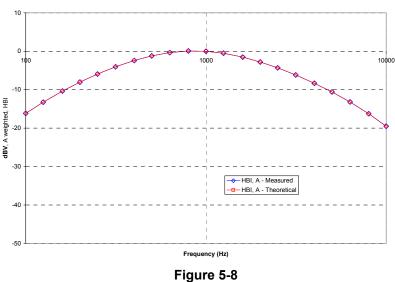
WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

ABM2 Frequency Response Validation					
	HBI, A -	HBI, A -			
f (Hz)	Measured	Theoretical	dB Var.		
	(dB re 1kHz)	(dB re 1kHz)			
100	-16.180	-16.170	-0.010		
125	-13.257	-13.250	-0.007		
160	-10.347	-10.340	-0.007		
200	-8.017	-8.010	-0.007		
250	-5.925	-5.920	-0.005		
315	-4.045	-4.040	-0.005		
400	-2.405	-2.400	-0.005		
500	-1.212	-1.210	-0.002		
630	-0.349	-0.350	0.001		
800	0.071	0.070	0.001		
1000	0.000	0.000	0.000		
1250	-0.503	-0.500	-0.003		
1600	-1.513	-1.510	-0.003		
2000	-2.778	-2.780	0.002		
2500	-4.316	-4.320	0.004		
3150	-6.166	-6.170	0.004		
4000	-8.322	-8.330	0.008		
5000	-10.573	-10.590	0.017		
6300	-13.178	-13.200	0.022		
8000	-16.241	-16.270	0.029		
10000	-19.495	-19.520	0.025		

Table 5-1 ABM2 Frequency Response Validation

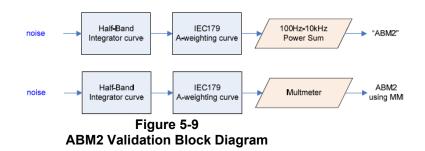
FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 11 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 11 01 50
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ABM2 Frequency Response Validation (LISTEN)



ABM2 Frequency Response Validation

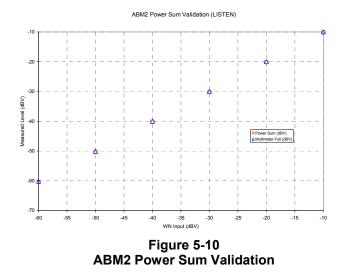
The ABM2 result is a power sum from 100 Hz to 10 kHz with half-band integration and Aweighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 5-9). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:



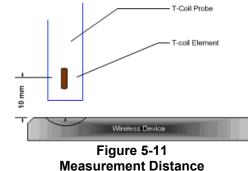
The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 5-2 ABM2 Power Sum Validation					
WN Input (dBV)	Dev (dB)				
-60	-60.36	-60.2	0.16		
-50	-50.19	-50.13	0.06		
-40	-40.14	-40.03	0.11		
-30	-30.13	-30.01	0.12		
-20	-20.12	-20	0.12		
-10	-10.14	-10	0.14		

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 12 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 12 01 30
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- 3. Measurement Test Setup
 - a. Fine scan above the WD (TEM)
 - i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below:



- ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the sound check system.
- iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 5-16 after a T-coil orientation was fully measured with the SoundCheck system.
- b. Speech Signal Setup to Base Station Simulator
 - i. C63.19 Table 7-1 states audio reference input levels for various technologies:

Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16
	TDMA (22 and 11 Hz)	-18

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 13 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 15 01 50
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The CMU200 audio levels were determined using base station simulator manufacturer calibration procedures resulting in the below corresponding voltages relative to handset test point level (in dBm0):

 Table 5-3 CMU200 Voltage Input Levels for Audio

 dBm0 Ref.
 Voltage
 Notes

 3.14 dBm0
 990.5 mV
 -0.08 dBV
 From GSM "DECODER CAL". (What is needed through Encoder for FS)

10.2 dP\/ Ear Spacebood/Handoot Low

-TO UBITIO	109.4 111	-19.2 UBV	For Speechcou/Hanuser Low
dBm0 Ref.	Voltage		Notes
3.14 dBm0	1068.5 mV		From UMTS "DECODER CAL". (What is needed through Encoder t FS)
-16 dBm0	118.0 mV	-18.6 dBV	For Handset Low
	dBm0 Ref. 3.14 dBm0	dBm0 Ref. Volt 3.14 dBm0 1068.5 mV	dBm0 Ref. Voltage 3.14 dBm0 1068.5 mV 0.58 dBV

- c. Real-Time Analyzer (RTA)
 - i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
- d. WD Radio Configuration Selection

16 dBm0

100.4 m

i. The device was chosen to be tested in the worst-case ABM2 condition under EFR (GSM); AMR 12.2 kbps (UMTS); (see below):

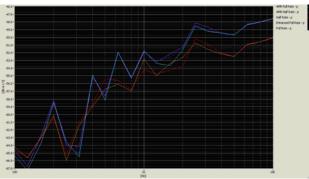


Figure 5-12 Vocoder Analysis for ABM Noise

- 4. Signal Quality Data Analysis
 - a. Narrow-band Magnetic Intensity
 - i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
 - b. Frequency Response
 - i. The appropriate frequency response curve was measured to curves in Figure 4-1 or Figure 4-2 between 300 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a.) A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 14 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 14 01 50
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ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 5-13. All R10 frequencies were plotted with respect to 0dB at 1 kHz value and aligned with respect to the EIA-504 mask.

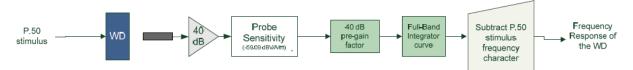


Figure 5-13 Frequency Response Block Diagram

- iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.
- c. Signal Quality Index
 - i. Ensuring the WD was at maximum RF power, maximum volume, backlight on, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.)
 - ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value
 - iii. This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

IV. Test Setup

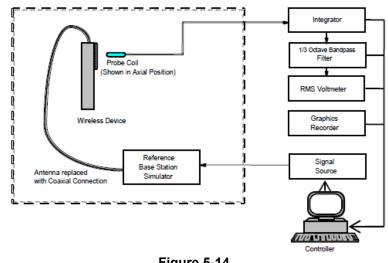


Figure 5-14 Audio Magnetic Field Test Setup

V. Deviation from C63.19 Test Procedure

None.

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 15 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 15 01 50	
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VI. Air Interface Technologies Tested

3G packet services were not tested for this device since they are considered 'Over-the-Top' applications and are not within the current definition of a managed CMRS service.

VII. Wireless Device Channels and Frequencies

The frequencies listed in the table below are those that lie in the center of the bands used for cellular telephony. Low, middle and high channels were tested in each band for FCC compliance evaluation to ensure the maximum emission is captured across the entire band.

To facilitate setting of a base station simulator for ABM measurements, specific band plan channel numbers are listed that may be used in lieu of the band center frequencies.

Center Channels and Frequencies					
Test frequencies & associated channels					
Channel Frequency (MHz)					
Cellular 850					
190 (GSM)	836.60				
4183 (UMTS)	836.60				
PCS 1900					
661 (GSM)	1880				
9400 (UMTS)	1880				

Table 5-4

VIII. RF Emission Effect on T-coil Measurements

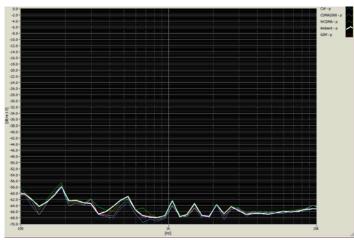


Figure 5-15 High power RF Emissions Effect with HAC Dipole on the T-coil Probe System 10mm between dipole maximum and magnetic probe

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 16 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 10 01 30	
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IX. Test Flow

The flow diagram below was followed (From C63.19):

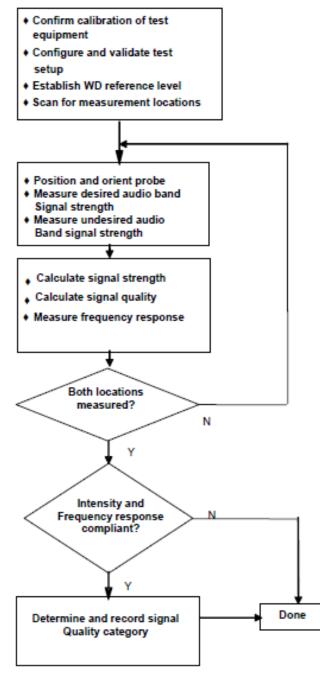


Figure 5-16 C63.19 T-Coil Signal Test Process

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 17 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 17 01 50	
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6. FCC 3G MEASUREMENTS

AMR at 12.2kbps, 13.6kbps SRB was used for the testing as the worst-case configuration for the handset. See below plot for ABM noise comparison between vocoder rates:

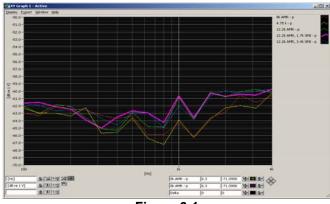


Figure 6-1 UMTS Audio Band Magnetic Noise

	Ι.	ABM	Measurements
--	----	-----	--------------

Table 6-1 FCC 3G ABM Measurements for ZNFC410

ABM2 Pre-Test (dBA/m), A, HBI

AMR 12.2kbps	AMR 7.95kbps	AMR 4.75kbps	Orientation	Channel
-59.99	-60.55	-60.37	Radial	4132

ABM1 Pre-Test (dBA/m)

AMR 12.2kbp	S .	AMR 7.95kbps	AMR 4.75kbps	Orientation	Channel
6.090		6.140	6.060	Radial	4132

• Mute on; Backlight off; Max Volume, Max Contrast

• UMTS: TPC="All 1s";



Figure 6-2 Audio Band Magnetic Curve Measurement Block Diagram

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 18 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage to 01 50	
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7. TEST SUMMARY

I. T-Coil Test Summary

Table of Results for GSM								
C63.19 Sec.	Mode	Band	Test Description	Minimum Limit*	Measured	Verdict		
				dBA/m	dBA/m	PASS/FAIL		
8.3.1			Intensity, Axial	-18	14.2	PASS		
8.3.1		I	Intensity, Radial	-18	6.2	PASS		
8.3.4	GSM	Cellular	Signal-to-Noise/Noise, Axial	20	35.3	PASS		
8.3.4			Signal-to-Noise/Noise, Radial	20	51.4	PASS		
8.3.2			Frequency Response, Axial	0	1.0	PASS		
8.3.1			Intensity, Axial	-18	14.1	PASS		
8.3.1			Intensity, Radial	-18	6.2	PASS		
8.3.4	GSM	PCS	Signal-to-Noise/Noise, Axial	20	39.2	PASS		
8.3.4			Signal-to-Noise/Noise, Radial	20	55.0	PASS		
8.3.2			Frequency Response, Axial	0	1.0	PASS		

Table 7-1 Table of Results for GSM

Table 7-2 Table of Results for UMTS

C63.19 Sec.	Mode	Band	Test Description	Minimum Limit*	Measured	Verdict
				dBA/m	dBA/m	PASS/FAIL
8.3.1	UMTS Cellular	Intensity, Axial	-18	14.3	PASS	
8.3.1			Intensity, Radial	-18	6.1	PASS
8.3.4		Signal-to-Noise/Noise, Axial	20	67.5	PASS	
8.3.4			Signal-to-Noise/Noise, Radial	20	65.8	PASS
8.3.2			Frequency Response, Axial	0	1.2	PASS
8.3.1			Intensity, Axial	-18	14.2	PASS
8.3.1			Intensity, Radial	-18	6.1	PASS
8.3.4	UMTS	UMTS PCS	Signal-to-Noise/Noise, Axial	20	67.5	PASS
8.3.4			Signal-to-Noise/Noise, Radial	20	66.0	PASS
8.3.2			Frequency Response, Axial	0	1.4	PASS

Note: The above summary tables represent the worst-case numerical values according to configurations in Tables 7-4 and 7-5.

FCC ID: ZNFC410		HAC (1-COIL) TEST REPORT		Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 19 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 19 01 30
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Consolidated Tabled Results							
	Volume Setting		Cellular		PCS		
		Axial	Radial	Axial	Radial		
Freq. Response Margin		PASS	N/A	PASS	N/A		
Magnetic Intensity Verdict	Maximum	PASS	PASS	PASS	PASS		
FCC SNR Verdict		PASS	PASS	PASS	PASS		

Table 7-3 Consolidated Tabled Results

Note: Result shown is for T-coil category only.

II. Raw Handset Data

Table 7-4 Raw Data Results for GSM							
	Volume	Cellular Band					
			Axial			Radial	
		128	190	251	128	190	251
ABM1, dBA/m		14.41	14.21	14.56	6.36	6.40	6.16
ABM2, dBA/m		-20.92	-21.19	-21.29	-44.99	-45.29	-45.20
Ambient Noise, dBA/m		-59.04	-59.04	-59.04	-60.92	-60.92	-60.92
Freq. Response Margin (dB)	Maximum	0.96	0.96	0.96	N/A	N/A	N/A
S+N/N (dB)		35.33	35.40	35.85	51.35	51.69	51.36
S+N/N per orientation (dB)			35.33			51.35	
	Volume	PCS Band					
			Axial	-	Radial		
		512	661	810	512	661	810
ABM1, dBA/m		14.19	14.12	14.44	6.22	6.45	6.27
ABM2, dBA/m		-25.40	-25.08	-25.03	-48.93	-48.76	-48.69
Ambient Noise, dBA/m		-59.04	-59.04	-59.04	-60.92	-60.92	-60.92
Freq. Response Margin (dB)	Maximum	0.97	0.97	0.97	N/A	N/A	N/A
S+N/N (dB)		39.59	39.20	39.47	55.15	55.21	54.96
S+N/N per orientation (dB)			39.20			54.96	
T-coil Coordinates (cm)	[x,y] from bottom left	2.6, 1.8 2.6, 2.7					

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 20 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 20 01 30	
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	Volume	Cellular Band					
			Axial			Radial	
		4132	4183	4233	4132	4183	4233
ABM1, dBA/m		14.35	14.36	14.30	6.10	6.12	6.12
ABM2, dBA/m		-53.21	-53.18	-53.49	-59.68	-60.15	-60.56
Ambient Noise, dBA/m		-59.04	-59.04	-59.04	-60.92	-60.92	-60.92
Freq. Response Margin (dB)	Maximum	1.25	1.38	1.23	N/A	N/A	N/A
S+N/N (dB)		67.56	67.54	67.79	65.78	66.27	66.68
S+N/N per orientation (dB)			67.54			65.78	
	Volume	PCS Band					
		Axial			Radial		
		9262	9400	9538	9262	9400	9538
ABM1, dBA/m		14.16	14.21	14.17	6.16	6.14	6.13
ABM2, dBA/m		-53.48	-53.25	-53.41	-60.36	-60.18	-59.91
Ambient Noise, dBA/m		-59.04	-59.04	-59.04	-60.92	-60.92	-60.92
Freq. Response Margin (dB)	Maximum	1.39	1.39	1.41	N/A	N/A	N/A
S+N/N (dB)		67.64	67.46	67.58	66.52	66.32	66.04
S+N/N per orientation (dB)			67.46			66.04	
T-coil Coordinates (cm)	[x,y] from bottom left	2.6, 1.8			2.6, 2.7		

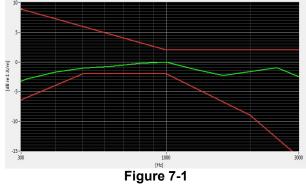
Table 7-5 Raw Data Results for UMTS

Notes:

- 1. Power Configuration: GSM850: PCL=5, GSM1900: PCL=0; UMTS: TPC="All 1s";
- Phone Condition: Mute on; Backlight off; Max Volume, Max Contrast
 Vocoder Configuration: EFR (GSM); AMR 12.2 kbps (UMTS);
 'Radial' orientation refers to radial transverse.

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 21 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 21 01 30
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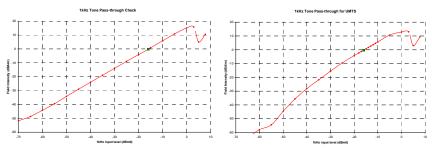
III. Frequency Response Graph



Axial Frequency Response

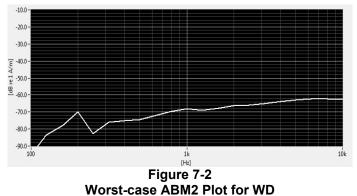
Note: User T-coil Mode (**Settings->Call Settings->Hearing aids**) was set to ON for Frequency Response compliance. This frequency response represents the worst-case ABM2 test configuration according to Tables 7-4 and 7-5.

IV. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements at -16 dBm0 for GSM and UMTS. This measurement was taken in the axial configuration above the maximum location.

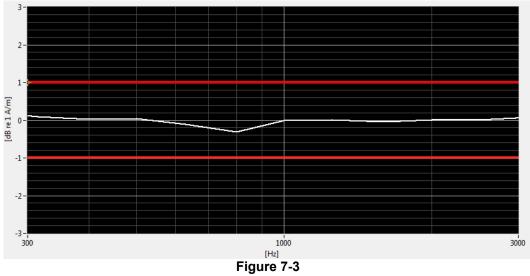
V. Undesirable Audio Magnetic Band Plot (ABM2)



Note: This plot represents the data from the location/configuration resulting in the highest ABM2 result shown in Tables 7-4 and 7-5.

FCC ID: ZNFC410	PCTEST	HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 22 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 22 01 30	
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VI. T-Coil Validation Test Results



Helmholtz Coil Validation for Frequency Response

Table 7-6
Helmholtz Coil Validation Table of Results

Item	Target	Result	Verdict
Signal Validation			
Frequency Response, from limits	0 ± 0.5 dB	0.30	PASS
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-10.050	PASS
Noise Validation			
Axial Environmental Noise	< - 58 dBA/m	-59.04	PASS
Radial Environmental Noise	< - 58 dBA/m	-60.92	PASS

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 23 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 23 01 30	
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8. MEASUREMENT UNCERTAINTY

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%	
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%	
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%	
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%	
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%	
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%	
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%	
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%	
Combined standard uncertainty	Combined standard uncertainty, uc (k=1)						0.71
Expanded uncertainty (k=2), 95% confidence level						35.3%	1.31

Table 8-1 Uncertainty Estimation Table

Notes:

1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.

2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in

NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager		
Filename:	Test Dates:	EUT Type:		Page 24 of 38		
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Faye 24 01 30		

EQUIPMENT LIST 9.

Table 9-1 **Equipment List**

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	E4407B	ESA Spectrum Analyzer	4/16/2013	Annual	4/16/2014	US39210313
Control Company	36934-158	Wall-Mounted Thermometer	1/4/2012	Biennial	1/4/2014	122014497
Gigatronics	80701A	(0.05-18GHz) Power Sensor	10/10/2012	Annual	10/10/2013	1833460
Gigatronics	8651A	Universal Power Meter	10/10/2012	Annual	10/10/2013	8650319
Listen	SoundCheck	Acoustic Analyzer System	10/4/2012	Annual	10/4/2013	979921
Listen	SoundConnect	Microphone Power Supply	4/22/2013	Annual	4/22/2014	PS2612
NI	4474	Data Acquisition Card	N/A		N/A	N/A
Rohde & Schwarz	CMU200	Base Station Simulator	5/3/2013	Annual	5/3/2014	836371/0079
Seekonk	NC-100	Torque Wrench (8" lb)	11/29/2011	Triennial	11/29/2014	21053
TEM	Radial T-Coil Probe	Radial T-Coil Probe	4/5/2013	Annual	4/5/2014	TEM-1130
TEM	Axial T-Coil Probe	Axial T-Coil Probe	4/5/2013	Annual	4/5/2014	TEM-1124
TEM	C63.19	Helmholtz Coil	4/5/2013	Biennial	4/5/2015	925
TEM		HAC System Controller with Software	N/A		N/A	N/A
TEM		HAC Positioner	N/A		N/A	N/A

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 25 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 25 01 50
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10. CALIBRATION CERTIFICATES

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 26 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 20 01 30
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Axial T Coil Probe Manufactured by: Xxial T Coil Probe Model No: Axial T Coil Probe Serial No: T EM-1124 Calibration Recall No: 22871 Bubmitted By: Submitted By: Customer: JUSTIN CHAO Address: 660-B DOBBIN ROAD Company: PCTEST ENGINEERING LAB Address: 660-B DOBBIN ROAD COLUMBIA MD 21045 The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter. West Caldwell Calibration Laboratories Procedure No. Axial T Coi TEM Upon receipt for Calibration, the instrument was found to be: Mthin Within (X) see attached Report of Calibration. He tolerance of the indicated specification. $\sqrt{3}C_4(ts/t3)$ Mote: Mylos Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025. Mote: With this Certificate, Report of Calibration Is included. $\sqrt{3}C_4(ts/t3)$ Note: With this Certificate, Report of Cal	Cerun		Calibia	
Manufactured by: TEM CONSULTING Model No: Axial T Coil Probe Serial No: TEM-1124 Calibration Recall No: 22871 Submitted By: Submitted By: Customer: JUSTIN CHAO Company: PCTEST ENGINEERING LAB Address: 6660-B DOBBIN ROAD COLUMBIA MD 21045 The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter. West Caldwell Calibration Laboratories Procedure No. Axial T Coi TEM Upon receipt for Calibration, the instrument was found to be: Within (X) see attached Report of Calibration. the tolerance of the indicated specification. West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025. VJSC. 4(15/13) Note: With this Certificate, Report of Calibration is included. Approved by: Calibration Date: 05-Apr-13		for		
Model No:Axial T Coil Probe Serial No:Serial No:TEM-1124 Calibration Recall No:Calibration Recall No:22871Submitted By:Submitted By:Customer:JUSTIN CHAOCompany:PCTEST ENGINEERING LAB Address:Address:G660-B DOBBIN ROAD COLUMBIAMD 21045The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.West Caldwell Calibration Laboratories Procedure No.Axial T Coi TEM Upon receipt for Calibration, the instrument was found to be: Within (X) see attached Report of Calibration.West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025. $\sqrt{3}$ C $4(15(13)$ Note: With this Certificate, Report of Calibration is included.Approved by:Calibration Date:05-Apr-13				
Calibration Recall No: 22871 Submitted By: Customer: JUSTIN CHAO Company: PCTEST ENGINEERING LAB Address: 6660-B DOBBIN ROAD COLUMBIA MD 21045 The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter. West Caldwell Calibration Laboratories Procedure No. Axial T Coi TEM Upon receipt for Calibration, the instrument was found to be: Within (X) see attached Report of Calibration. the tolerance of the indicated specification. Jose (4/15/13) West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025. Jose (10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025. Jose (21) Jose (21) Mote: With this Certificate, Report of Calibration is included. Approved by: Calibration Date: 05-Apr-13		_		
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	Note: With this Certificate, Rep	port of Calibration is included.	Approved by:	
Certificate No: 22871 - 1 Felix Christopher (QA Mgr.) ISO/IEC 17025:2005	Calibration Date: (05-Apr-13	Fr.	
ISO/IEC 17025:2005	Certificate No:	228 71 - ¹	Felix Christoph	ner (QA Mgr.)
QA Doc. #1051 Rev. 2.0 10/1/01 Certificate Page 1 of 1		Certificate Pa	ge 1 of 1	7025:2005
West Caldwell				
Uncompromised calibration Laboratories, Inc.				1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1

PCT ASSET # 80578

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Filename:	Test Dates:	EUT Type:		Page 27 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 27 01 50
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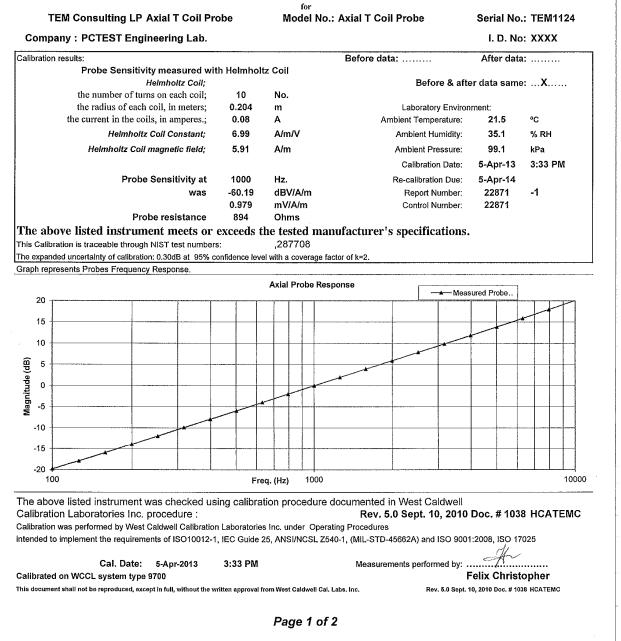






ACCREDITED Calibration Lab. Cert. # 1533.01

REPORT OF CALIBRATION



FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 28 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		1 age 20 01 00
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West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Axial T Coil Probe

for Model No.: Axial T Coil Probe

Serial No.: TEM1124

Company : PCTEST Engineering Lab.

Test	Function	Tolera	Measured values			
				Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.	dBV/A/m	-60.19		
			dB			
2.0	Probe Level Linearity		6	6.03		
		Ref. (0 dB)	0	0.00		
			-6	-6.03		
			-12	-12.06		
			Hz			
3.0	Probe Frequency Response		100	-19.8		
			126	-17.9		
			158	-15.9		
			200	-13.9		
			251	-11.9		
			316	-9.9		
			398	-7.9		
			501	-6.0		
			631	-4.0		
			794	-2.0		
		Ref. (0 dB)	1000	0.0		
			1259	2.0		
			1585	4.0		
			1995	5.9		
			2512	7.9		
			3162	9.9		
			3981	11.9		
			5012	13.9		
			6310	15.9		
			7943	18.0		
			10000	20.1		

	Instruments used for calibration:				Date of Cal.	Traceablity No.	Due Date
1	HP	34401A	S/N	US360641	8-Oct-2012	,287708	8-Oct-2013
	HP	34401A	S/N	US361024	8-Oct-2012	,287708	8-Oct-2013
1	HP	33120A	S/N	S3604371	8-Oct-2012	,287708	8-Oct-2013
	B&K	2133	S/N	1583254	9-Dec-2012	683/281764-12	10-Dec-2013

Cal. Date: 5-Apr-2013 3:33 PM Calibrated on WCCL system type 9700

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Tested by: Felix Christopher

Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCATEMC

Page 2 of 2

FCC ID: ZNFC410	PCTEST	HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 29 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 29 01 30
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West C	aldwell Calil	bration L	aboratories Inc.	
Cart	ficato	f	libration	
Ceru	ncate		alibration	
		for		
	Manufactured by		A CONSULTING	
	Model No: Serial No:	TEN	ial T Coil Probe A-1130	
	Calibration Reca	ll No: 2283 1bmitted By:	71	
	Customer:	JUSTIN CHA	0	S.
	Company: Address:	PCTEST ENG 6660-B DOBB	INEERING LAB	
	Address.	COLUMBIA	MD 21045	
The subject instrument	was calibrated to the i	ndicated specifi	cation using standards traceable to	o the
National Institute of St This document certifie	andards and Technolog s that the instrument m	gy or to accepted et the following	l values of natural physical consta specification upon its return to the	ats.
submitter.				
West Caldwell Calibra		cuure rite.	Radial T C TEM	
Upon receipt for Calib	ration, the instrument	was found to be:		
Within	(X) see attac	hed Report of C	alibration.	
the tolerance of the ind	icated specification.			
West Caldwell Calibra 10012-1 MH STD-456	tion Laboratories' calil 62A, ANSI/NCSL Z54(oration control s)-1, IEC Guide 2	ystem meets the requirements, ISC 5, ISO 9001:2008 and ISO 17025.	
		_,	1-15	
			4/15/13	
Note: With this Certificate,	Report of Calibration is incl	uded.	Approved by:	
Calibration Date:	05-Apr-13		FC.	- 193
Certificate No:	22871 - 2		Felix Christopher (QA Mgr.) ISO/IEC 17025:2005	
QA Doc. #1051 Rev. 2.0 10/1/01	Certifica Certifica	ate Page 1 of 1		
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FCC ID: ZNFC410	PCTEST	HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
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0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 50 01 50	
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HCRTEMC_TEM1130_Apr-05-2013



1575 State Route 96, Victor NY 14564



Calibration Lab. Cert. # 1533.01

REPORT OF CALIBRATION

TEM Consulting LP Radial T Coll Probe			Model No.: Radial T Coil Probe					Serial No.: TEM1130							
Company : PCTEST Engineering Lab.										I. D. No	: XXXX	ζ.			
libratio	on results:		, ,, ,,, ,,, ,,,							Before	data:		After data	ı:	
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			e coils, in ar			.08		A			Ambient Tem	ory Enviror	21.5	°C	
	uie cuii		oltz Coil Co			.98		/m/\	,		Ambient F		35.1	% RH	
	н		Coil magnet			.91		A/m	•		Ambient F	-	99.1	kPa	
	116	ennionz (son magnet	ic neia,	5			~//0				on Date:	5-Apr-13	3:56 F	n <i>n</i>
		Dr	obe Sensif	tivity of	4/	000		Hz.			Re-calibrat		5-Apr-13	3.50 P	143
		PD	ope sensi	was		0.36		nz. dBV//	۸lm			Number:	5-Apr-14 22871	-2	
				was		959		mV/A			-	Number:	22871	-	
			Probe resi	istance		98		Ohm			2001				
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librat	tion Labora	atories li	nc. proced	lure :						Rev	v. 5.0 Sept. 1	0, 2010	Doc. # 103	8 HCRI	FEMC
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nded	to implement	t the requi	rements of I	SO10012-	-1, IEC	Guide	e 25,	ANSI/	NCS	L Z540-1, (MIL-S	TD-45662A) and	1150 900	1:2008, ISO 17	025	
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ibrato	ed on WCCL	Cal. Dat	•	r-2013	3:5	6 PM	I			Meas	surements perfo	•	 Felix Christ	onhor	
	ent shall not be			without the	written -	oprovo	from	Monto	aldura	I Cal Labs Inc			10, 2010 Doc. # 10	•	c
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Filename:	Test Dates:	EUT Type:		Page 31 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 51 01 50
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HCRTEMC_TEM1130_Apr-05-2013

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Radial T Coil Probe

for Model No.: Radial T Coil Probe

Serial No.: TEM1130

Company : PCTEST Engineering Lab.

Test	Function	Tolera	Measured values			
				Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.	dBV/A/m	-60.36		
			dB			
2.0	Probe Level Linearity		6	6.03		
		Ref. (0 dB)	0	0.00		
			-6	-6.03		
			-12	-12.05		
			Hz			
3.0	Probe Frequency Response		100	-19.8		
			126	-17.9		
			158	-15.9		
			200	-13.9		
			251	-11.9		
			316	-9.9		
			398	-7.9		
			501	-6.0		
			631	-4.0		
			794	-2.0		
		Ref. (0 dB)	1000	0.0		
			1259	2.0		
			1585	4.0		
			1995	5.9		
			2512	7.9		
			3162	9.9		
			3981	11.9		
			5012	13.9		
			6310	15.9		
			7943	18.0		
			10000	20.1		

Instruments used for calibration	n:		Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N US360641	8-Oct-2012	,287708	8-Oct-2013
HP	34401A	S/N US361024	8-Oct-2012	.287708	8-Oct-2013
HP	33120A	S/N S3604371	8-Oct-2012	,287708	8-Oct-2013
B&K	2133	S/N 1583254	9-Dec-2012	683/281764-12	10-Dec-2013

Cal. Date: 5-Apr-2013 3:56 PM Tested by: Felix Christopher

Calibrated on WCCL system type 9700

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Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCRTEMC

Page 2 of 2

FCC ID: ZNFC410	<u> PCTEST</u>	HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 32 of 38	
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 52 01 50	
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11. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 33 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 33 01 30
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Filename:	Test Dates:	EUT Type:		Page 34 of 38
0Y1307251417-R1.ZNF	7/25/2013	Portable Handset		Fage 34 01 30
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FCC ID: ZNFC410		HAC (T-COIL) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 35 of 38	
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